

Special Issue

Fault Identification and Prognosis for Electromechanical Systems

Message from the Guest Editors

Fault identification and failure prognosis for electromechanical systems have become very important for most industrial sectors and for academic research. Fault identification includes fault detection, fault isolation, estimation of failure modes of faults, and fault severity estimation. This Special Issue's scope is on novel research and developments, related to:

- Fault detection;
- Fault isolation;
- Estimation of failure modes of faults;
- Fault severity estimation;
- Failure prognosis.

This Special Issue will not cover non-novel “case study” papers and papers, related to software fault prediction. Potential authors need to make clear statements of paper novelties, which should be based on comprehensive state-of-the art reviews.

Guest Editors

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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

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